

Test Report

HSI-CHIN ELECTRONICS CO., LTD.
 4F, NO. 194, SEC. 3, TA TUNG RD., HSI CHIH CITY,
 TAIPEI HSIEN, TAIWAN, R.O.C.

Report No. : CE/2006/13950
 Date : 2006/01/20
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The following merchandise was (were) submitted and identified by the client as :

Type of Product : TRAY: 真空盒 (PET)
Style/Item No : TRAY: 真空盒 (PET)
Sample Received : 2006/01/13
Testing Date : 2006/01/13 TO 2006/01/20

Test Result

PART NAME NO.1 : TRANSPARENT PLASTIC

PASS

Test Item (s):	Unit	Method	MDL	Result	Spec.
				No.1	
94/62/EC (Heavy metal content)					
Chromium VI (Cr+6)	ppm	UV-VIS after reference to US EPA 3060A.	2	N.D.	-
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B:2001 or other acid digestion.	2	N.D.	-
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.	2	7.2	-
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid	2	N.D.	-
Total Lead+Cadmium+Mercury+Chromium VI	ppm	Total Lead+Cadmium+Mercury+Chromium VI (94/62/EC)	-	7.2	100

NOTE: (1) N.D. = Not detected (<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit
 (4) " - " = Not Regulation


 Daniel Yeh, M.R. / Operation Manager
 Signed for and on behalf of
 SGS TAIWAN LTD.

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